Beyond Distinct Counting: LogLog Composable Sketches of frequency statistics

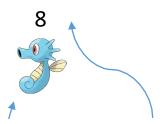
Edith Cohen





Tel Aviv University

Un-aggregated data



■ Data element $e \in D$ has key and value (e.key, e.value)















• Weight "frequency" of a key x: $w_x = \sum_{e \in D \mid e.key = x} e. \text{ value}$

Will also use:

 $\max_{x} m_x = \max_{e \in D} e. \text{value}$

8 5 4 10







frequencies of keys)

2× 7

1× 11

"density" W of

1× 17

f-statistics: $f(W) = \sum_{x \in X} f(w_x)$

$$f$$
- statistics $f(W) = \sum_{x \in X} f(w_x)$

- Distinct f(w) = 1 (w>0) #of distinct keys
- \blacksquare Sum f(w) = w
- Frequency moments $f(w) = w^p$
- $\text{Cap: } f(w) = \min(T, w)$
- Complement Laplace transform: $f(w) = 1 e^{-wt}$
- Other: $f(x) = \log(1 + x) f(x) = \min(x^{0.75}, T)$

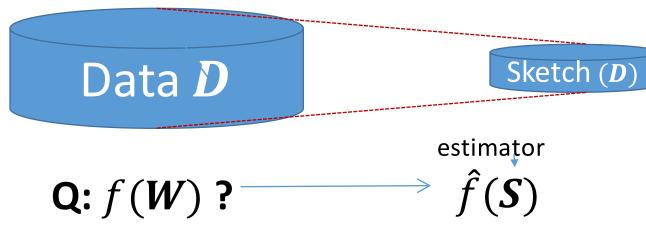
<u>Applications:</u> Search queries, online interactions, online transactions, word/term (co)-occurrences in corpus, network traffic

Issue: Aggregated view W is costly: Data movement, storage, computation Use sketches!



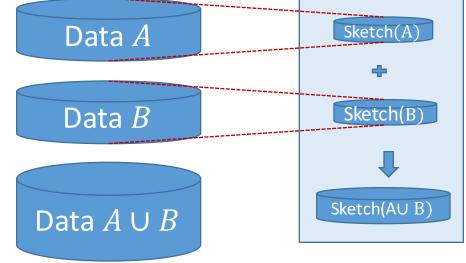
Sketches

A sketch for f is a lossy summary of the data D from which we can approximate (estimate) f(D) = f(W)



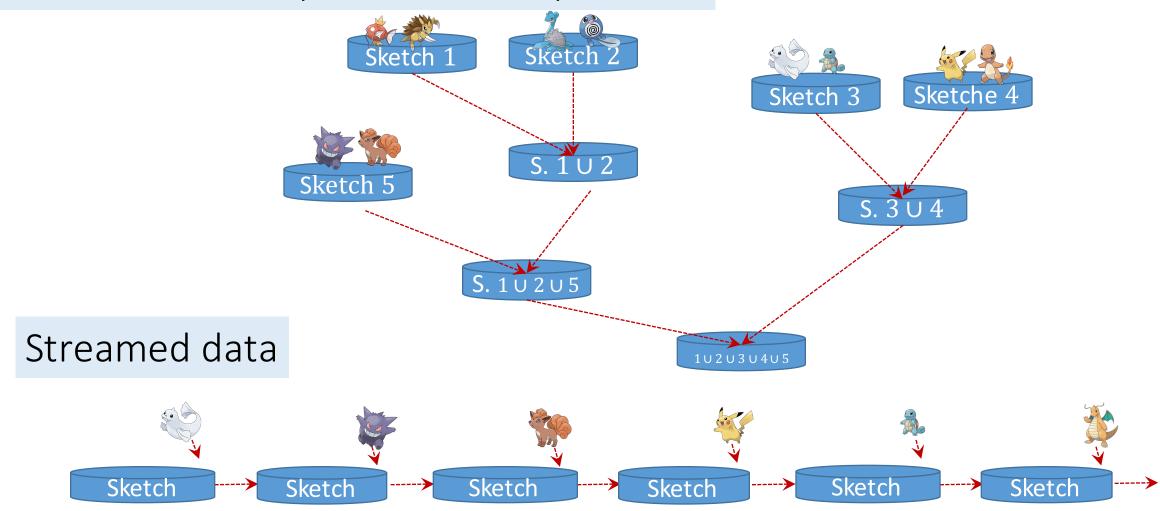
Sketch structure design goals:

- Optimize sketch-size vs. estimate quality
 - Can we get size $O(\epsilon^{-2} + \log \log n)$?
- Composable/mergeable



Why composable is useful?

Distributed data/parallelize computation



Approximate statistics via small sketches

- Data element $e \in D$ has key and value (e.key,e.value)
- Weight of key x is the Sum of its element values: $w_x = \sum_{e \in D} e.value$
- f-statistics: $f(D) = f(W) = \sum_{x \in X} f(w_x)$

Quality: Coefficient of variation $\frac{\sigma}{\mu} = \epsilon$, concentration

- ✓ Distinct f(w) = 1 (x > 0): [Flajolet Martin '85, Flajolet et al '07] $O(\epsilon^{-2} + \log \log n)$
- ✓ Sum f(w) = w: [Morris '77] $O(\epsilon^{-2} + \log \log n)$
 - Frequency moments $f(w) = w^p$: [Alon Matias Szegedy '99, Indyk '01] $O(\epsilon^{-2}\log^2 n)$
 - Capping $f(w) = \min(T, w)$ [C' 15] (via sampling) $O(\epsilon^{-2} \log n)$
 - Others: "universal" sketches [Braverman Ostrovsky '10] Polynomial(ϵ^{-1} , log n)

Sum: $\sum_{x \in X} f(w_x)$

log(n): A single register of size to keep the sum. Clearly composable

 $O(\epsilon^{-2} + \log \log n)$: [Morris 1977] +[Flajolet 1985] Composable version [C' 15]:

Maintain the "exponent" t, initialized $t \leftarrow 0$

- Estimate: return $(1+\epsilon)^t 1$
- Add Y:
 - Increase t by maximum amount so that estimate increase by $Z \leq Y$
 - Let $\Delta = Y Z$
 - Increment t with probability $\frac{\Delta \epsilon}{(1+\epsilon)^t}$
- Merge $t_2 \le t_1$: same as Add $(1 + \epsilon)^{t_2} - 1$ to counter t_1

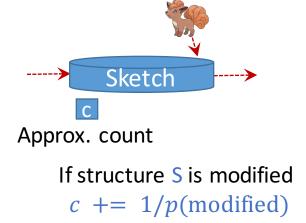
Distinct count sketches

HyperLogLog [Flajolet et al 2007]

- Optimal size $O(\epsilon^{-2} + \log \log n)$ for CV $\frac{\sigma}{\mu} = \epsilon$; n distinct keys
- Idea: store $k = \epsilon^{-2}$ exponents of hashes. Exponents value concentrated so store one and k offsets.

HIP estimators [Cohen '14, Ting '15]: halve the variance to $\frac{1}{2k}$!

Idea: track an estimated count c with sketch structure. When structure is modified, add inverse modification probability to c.



Distinct count sketches

*Simplified version [C'94]

- Initialize: $k = \epsilon^{-2}$ registers $c_1, ..., c_k, \leftarrow \infty$;
 - Hash functions $H_i(x) \sim Exp[1]$
- Process element *e. key*:
 - For $i \in [k]$: $c_i \leftarrow \min(c_i, H_i(e. key))$
- Estimate: $\frac{k-1}{\sum_i c_i}$

Analysis:

- $c_i \sim \text{minimum over active keys of independent } EXP[1] \implies c_i \sim EXP[\text{Distinct}(D)]$
- Parameter estimation problem

Reduce size: keep exponents only of c_i , one exponent and ϵ^{-2} constant-size offsets

Composability: minimum is composable

MaxDistinct sketches

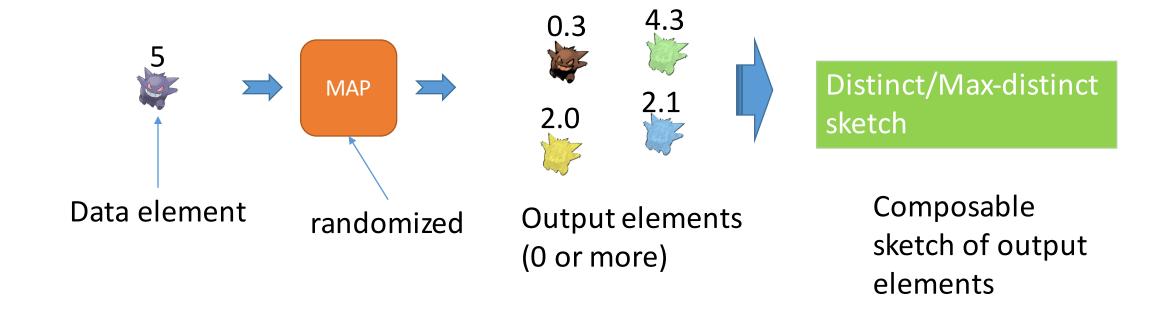
- Max value of an element with key x: $m_x = \max_{e \in D} e.key = x$
- \blacksquare MaxDistinct(D) = $\sum_{\mathbf{x}} m_{\mathbf{x}}$
- Initialize:
 - $k = \epsilon^{-2}$ registers $c_1, ..., c_k, \leftarrow \infty$
 - Hash functions $H_i(x) \sim Exp[1]$
- Process element (e. key, e. value):
 - For $i \in [k]$: $c_i \leftarrow \min(c_i, \frac{H_i(e.key)}{e.value})$
- Estimate: $\frac{k-1}{\sum_i c_i}$

Analysis:

- For each key x, the minimum over elements of $\frac{H_i(e.key)}{e.value} \sim EXP[m_x]$
- $c_i \sim \text{minimum over keys } x \text{ of independent } EXP[m_x] \Longrightarrow$

$$c_i \sim EXP[MaxDistinct(D)]$$

Element processing framework



Q: For which f we can do this? How? (specify MAP)

Goal: E[MaxDistinct($\bigcup_{e \in D} MAP(e)$)] = f(W), + concentration

(Soft) cap functions

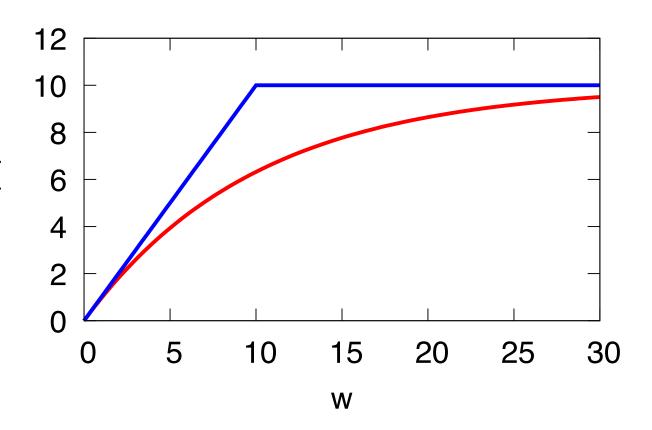
$$\widetilde{\operatorname{cap}}_{T}(w) = T\left(1 - e^{-\frac{w}{T}}\right)$$

$$\operatorname{cap}_{T}(w) = \min(T, w)$$

$$W = \begin{bmatrix} 11 & 7 & 3 & 1 \\ \hline & & & & \\ \end{bmatrix}$$

(aggregated D)

$$cap_3(W) = \sum_{x \in W} min(3, w_x) = 10$$



$$cap_3(W) = \sum_{x \in W} min(3, w_x) = 10$$
 $\widetilde{cap}_3(W) = 3 \sum_{x \in W} (1 - e^{-\frac{w_x}{3}}) \approx 8.38$

Warm Up: Sketching cap_T-statistics

we work with
$$f_t(w) = 1 - e^{-wt}$$

!! The statistics is the Laplace^c (complement-Laplace) transform of $L^{c}[W](t) = \sum_{i=1}^{n} (1 - e^{-w_{x}t})$ W (density function of frequencies)



$$L^{c}[W](t) = \sum_{x} (1 - e^{-w_{x}t})$$

 $\widetilde{\operatorname{cap}}_T$ -statistics is $T \times \operatorname{Laplace}^c$ transform at point $t = \frac{1}{T}$

since
$$\widetilde{\text{cap}}_T(w) = Tf_{1/T}(w)$$

$$\widetilde{\operatorname{cap}}_{T}(W) = \sum_{x} \widetilde{\operatorname{cap}}_{T}(w) = T \sum_{x} f_{\frac{1}{T}}(w_{x}) = TL^{c}[W](1/T)$$

Sketching Laplace transform of W at point t

$$f_t(w) = 1 - e^{-wt}$$



Input: e = (e.key, e.value)

For
$$i = 1, ..., r$$

- $\mathbf{y}_i \sim \text{EXP}[e.value]$
- If $y_i \le t$: output e.key#i

Output: (approximate) number of distinct output keys



! Output sketch size is barely affected by r, only element processing

Claim: (correctness)

$$\frac{1}{r} \mathbf{E} \left[\text{Distinct} \left(\bigcup_{e \in D} \mathbf{MAP}(e) \right) \right] = \sum_{x} 1 - e^{-w_{x}t} = L^{c}[W](t)$$

Input: e = (e.key, e.value)For i = 1, ..., r

- $y_i \sim \text{EXP}[e.value]$
 - If $y_i \le t$: output e.key#i

!! Each input key x and $i \in [r]$ have a unique potential output key x#i

We compute the probability that the output key x#i is generated:

 \Leftrightarrow y_i $\leq t$ for at least one element $e \in D$ with e. key = x

 $\Leftrightarrow \min_{e \mid e.key = x} EXP[e.value] \le t$

 $\iff \text{EXP}[w_x] \le t = 1 - e^{-w_x t}$

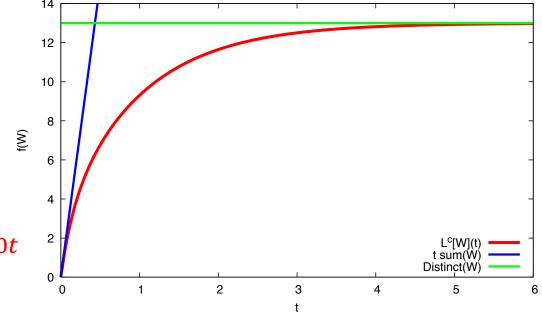
Sum over all x, i (Poisson rvs) to establish claim

Subtlety: ? We need "enough" $\geq \epsilon^{-2}$ distinct output keys for low error. We set $r = O(\epsilon^{-2})$, but still need to address small t ...

•
$$\frac{1}{r}$$
 E[Distinct($\bigcup_{e \in D} MAP(e)$)] = $\sum_{x} 1 - e^{-w_x t} = L^c[W](t)$

"density"
$$W$$
 of frequencies:
 $10 \times w_x = 1$
 $2 \times w_x = 5$
 $1 \times w_x = 10$

- Sum(W) = 30
- *Distinct(W)=13*
- $L^{c}[W](t) = 13 10e^{-t} 2e^{-5t} e^{-10t}$



At the regime with low distinct count we can use $L^{c}[W](t) \approx tSum(W)$

f(w) in the nonnegative span of $g_t(w) = 1 - e^{-wt}$

• Any function f(w) that can be expressed $a(t) \ge 0$ as:

$$f(w) = \int_0^\infty a(t)(1 - e^{-wt})dt = L^c[a](w)$$

We get
$$a(t) = L^{c-1}[f(w)](t) = \frac{1}{t}L^{-1}[\frac{\partial f(w)}{\partial w}](t)$$

Span includes all concave sublinear f without "sharp" corners: low frequency moments $p \le 1$; logarithms; soft capping functions ...

f(w)	$T(1-e^{-\frac{w}{T}})$	\sqrt{w}	$\log(1+w)$
a(t)	$T\delta(t-\frac{1}{T})$	$\frac{1}{2\sqrt{\pi}}t^{-1.5}$	$\frac{e^{-t}}{t}$

Sketching statistics for f in the nonnegative span...

$$f(w) = \int_0^\infty a(t)(1 - e^{-wt})dt = L^c[a](w) \qquad a(t) \ge 0$$

$$f(W) = \int_0^\infty f(w)W(w)dw = \int_0^\infty W(w) \int_0^\infty a(t)(1 - e^{-wt})dt dw =$$

$$= \int_0^\infty a(t) \int_0^\infty W(w)(1 - e^{-wt}) dw dt$$

$$= \int_0^\infty a(t) L^c[W](t)dt \qquad \text{statistics } f(W) \text{ expressed in terms of the } L^c \text{ transform}$$

 \Rightarrow Can sketch $L^c[W](t)$ at many points t. But we will see a better way...

Sketching
$$f(W) = \int_0^\infty a(t) L^c[W](t) dt$$

• Idea: Modify the element map for point t to work with weighted combination of t values



point t

Input: e = (e.key, e.value)

For i = 1, ..., r

- $y_i \sim \text{EXP}[e. value]$
- If $y_i \le t$: output e.key#i

Distinct count sketch

combination a(t) *slightly simplified

Input: e = (e.key, e.value)

For i = 1, ..., r

- $y_i \sim \text{EXP}[e.value]$
- output (e.key#i, $\int_{y_i}^{\infty} a(t) dt$)

MaxDistinct sketch

Extension: Multi-objective sketch of the span

- $\underline{\text{Idea:}}$ If we can sketch all t values together, we can use the sketch for all statistics in the span
- log factor increase in sketch size (analysis of all-distance sketches [C' 94,15])

point *t*

Input: e = (e.key, e.value)

For i = 1, ..., r

- $y_i \sim \text{EXP}[e. value]$
- If $y_i \le t$: output e.key#i

Distinct count sketch

All t

Input: e = (e.key, e.value)

For i = 1, ..., r

- $\mathbf{y}_i \sim \text{EXP}[e.value]$
- output (e.key#i, y_i)

"All-threshold" sketch

All-threshold Distinct sketches

Input elements (e. key, e. value)

Sketch allows us to approximate for any t: Distinct $\{e, key \mid e, value \leq t\}$

Distinct counting sketch

- Initialize: $k = \epsilon^{-2}$ registers $c_1, ..., c_k, \leftarrow \infty$;
 - Hash functions $H_i(x) \sim Exp[1]$
- Process element *e. key*:
 - For $i \in [k]$: $c_i \leftarrow \min(c_i, H_i(e. key))$
- Estimate: $\frac{k-1}{\sum_i c_i}$

All-threshold Distinct sketch

"Remember" for each register c_i all "breakpoints" where the minimum increases

- Logarithmic number of breakpoints [C' 94]
- Any "sample-based" distinct sketch can be similarly extended [C' 15]

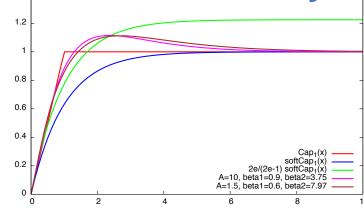
Handling sharp corners: All concave sublinear f

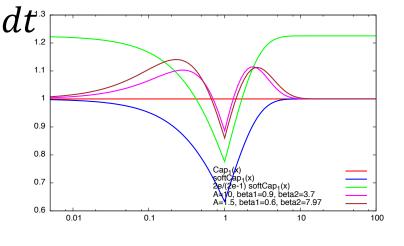
Reduces to sketching $Cap_1(w) = min(1, w)$

■ Soft cap gives $\left(1 - \frac{1}{e}\right) \times$ approximation

Better approximation:

- Use a signed inverse transform to approximate $\operatorname{Cap}_1(w)$, controlling the $L_1(a(t)) = \int_0^\infty |a(t)| \, dt$
- Separate estimate the negative and positive components
- Grid search on 3 points \Rightarrow We get 12%
- Open question to get ϵ





Conclusion

Summary:

- Simple, practical design of composable double-logarithmic size sketching for concave sublinear statistics
- Results novel theoretically even with $O(\epsilon^{-2} \log n)$ size

Open:

- Handling statistics with "sharp corners".
- Loglog in the super-linear regime (second moment?)





Thank you!









